

RMWB24001

24 GHz Buffer Amplifier MMIC

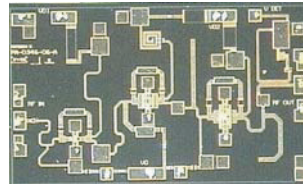
General Description

The RMWB24001 is a 3-stage GaAs MMIC amplifier designed as an 17 to 24 GHz Buffer Amplifier for use in point to point and point to multi-point radios, and various communications applications. In conjunction with other amplifiers, multipliers and mixers it forms part of a complete 23 and 26 GHz transmit/receive chipset. The RMWB24001 utilizes our 0.25 μ m power PHEMT process and is sufficiently versatile to serve in a variety of medium power amplifier applications.

Features

- 4 mil Substrate
- Small-signal Gain 25dB (typ.)
- Saturated Power Out 17dBm (typ.)
- Voltage Detector Included to Monitor Pout
- Chip size 2.5mm x 1.5mm x 100 μ m

Device



Absolute Ratings

Symbol	Parameter	Ratings	Units
V _d	Positive DC Voltage (+4V Typical)	+6	V
V _g	Negative DC Voltage	-2	V
V _{dg}	Simultaneous (V _d -V _g)	8	V
I _D	Positive DC Current	110	mA
P _{IN}	RF Input Power (from 50 Ω source)	+11	dBm
T _C	Operating Baseplate Temperature	-30 to +85	°C
T _{STG}	Storage Temperature Range	-55 to +125	°C
R _{JC}	Thermal Resistance (Channel to Backside)	148	°C/W

Electrical Characteristics (At 25°C, 50Ω system, Vd = +4V, Quiescent Current Idq = 70mA)

Parameter	Min	Typ	Max	Units
Frequency Range	17		24	GHz
Gate Supply Voltage ¹ (Vg)		-0.2		V
Gain (Small Signal Pin = 10dBm)	13	15	18	dB
Gain Variation vs. Frequency		2.0		dB
Power Output Saturated: (Pin = +5dBm)	14	17	19	dBm
Drain Current at Psat		80		mA
Power Added Efficiency (PAE): at Psat		15		%
Input Return Loss (Pin = -10dBm)		12		dB
Output Return Loss (Pin = -10dBm)		12		dB
DC Detector Voltage at Pout = 17dBm		1.0		V

Note:

1: Typical range of gate voltage is -0.5 to 0V to set typical Idq of 70mA.

Application Information

CAUTION: THIS IS AN ESD SENSITIVE DEVICE.

Chip carrier material should be selected to have GaAs compatible thermal coefficient of expansion and high thermal conductivity such as copper molybdenum or copper tungsten. The chip carrier should be machined, finished flat, plated with gold over nickel and should be capable of withstanding 325°C for 15 minutes.

Die attachment should utilize Gold/Tin (80/20) eutectic alloy solder and should avoid hydrogen environment for PHEMT devices. Note that the backside of the chip is gold plated and is used as RF and DC ground.

These GaAs devices should be handled with care and stored in dry nitrogen environment to prevent contamination of bonding surfaces. These are ESD sensitive devices and should be handled with appropriate precaution including the use of wrist grounding straps. All die attach and wire/ribbon bond equipment must be well grounded to prevent static discharges through the device.

Recommended wire bonding uses 3 mils wide and 0.5 mil thick gold ribbon with lengths as short as practical allowing for appropriate stress relief. The RF input and output bonds should be typically 0.012" long corresponding to a typical 2 mil gap between the chip and the substrate material.

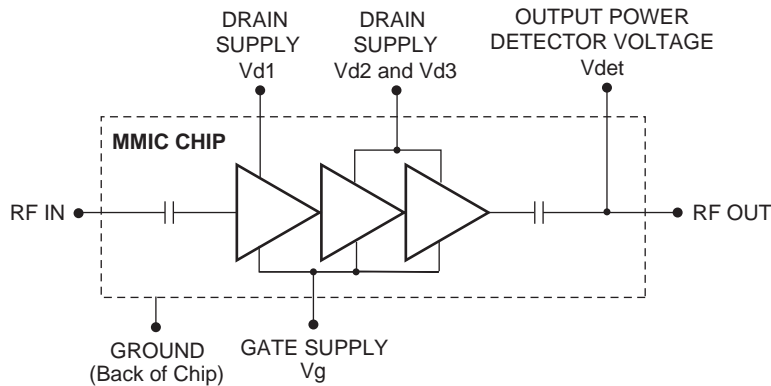
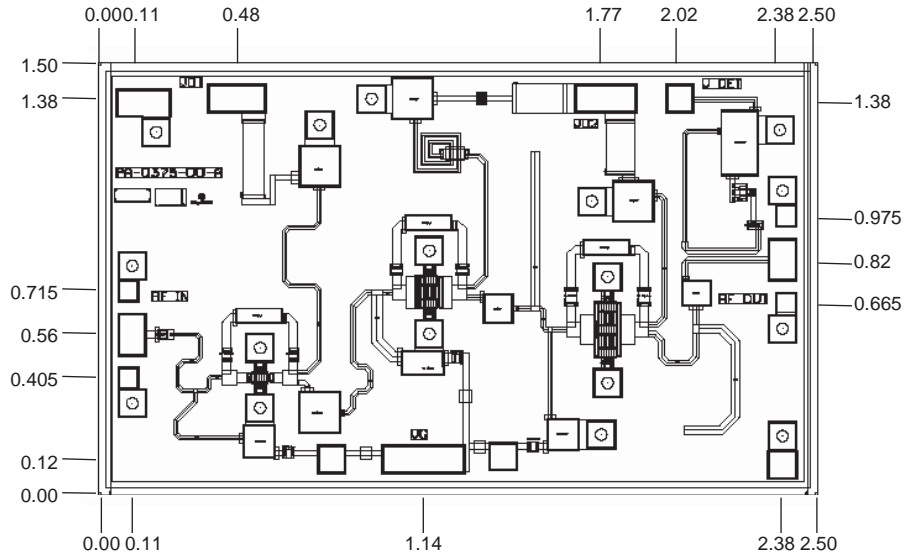


Figure 1. Functional Block Diagram¹

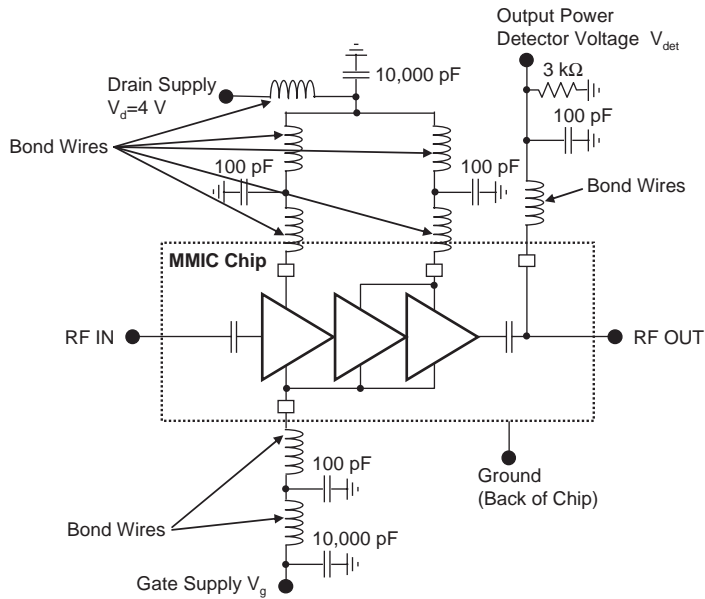
Note:

1: Detector delivers >0V DC into 3kΩ load resistor for > +17dBm output power. If output power level detection is not desired, do not make connection to detector bond pad.



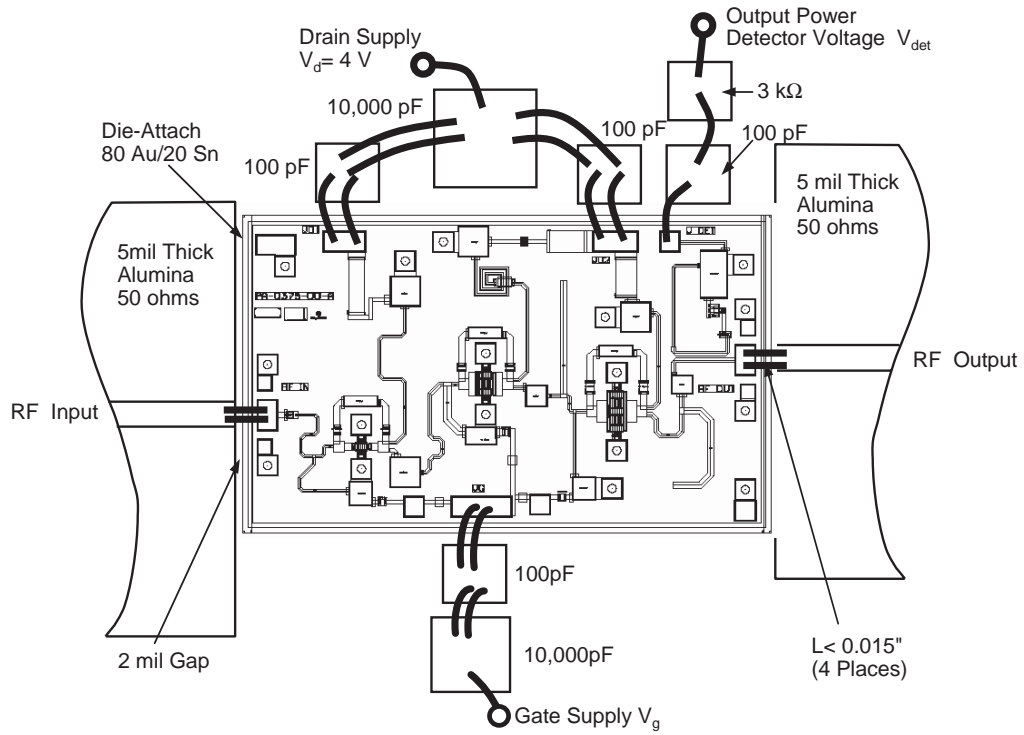
Dimensions in millimeters

Figure 2. Chip Layout and Bond Pad Locations
Chip Size is 2.50mm x 1.50mm X 100µm. Back of chip is RF and DC Ground.



Note:
 Detector delivers > 0.1 V DC into 3 kΩ load resistor for > +17 dBm output power. If output power level detection is not desired, do not connect to detector bond pad.

Figure 3. Recommended Application Schematic Circuit Diagram



Note:
Use 0.003" by 0.0005" Gold Ribbon for bonding. RF input and output bonds should be less than 0.015" long with stress relief.

Figure 4. Recommended Assembly Diagram

Recommended Procedure for Biasing and Operation

CAUTION: LOSS OF GATE VOLTAGE (V_g) WHILE DRAIN VOLTAGE (V_d) IS PRESENT MAY DAMAGE THE AMPLIFIER CHIP.

The following sequence of steps must be followed to properly test the amplifier:

Step 1: Turn off RF input power.

Step 2: Connect the DC supply grounds to the ground of the chip carrier. Slowly apply negative gate bias supply voltage of -1.5V to V_g .

Step 3: Slowly apply positive drain bias supply voltage of +4V to V_d .

Step 4: Adjust gate bias voltage to set the quiescent current of $I_{dq} = 70\text{mA}$.

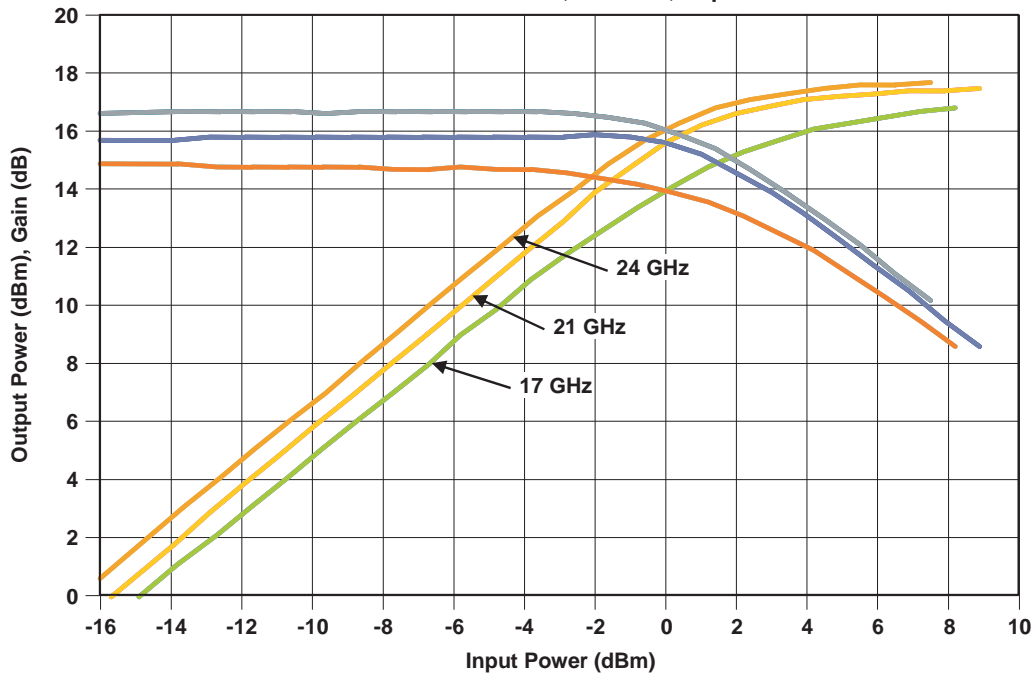
Step 5: After the bias condition is established, the RF input signal may now be applied at the appropriate frequency band.

Step 6: Follow turn-off sequence of:

- (i) Turn off RF input power,
- (ii) Turn down and off drain voltage (V_d),
- (iii) Turn down and off gate bias voltage (V_g).

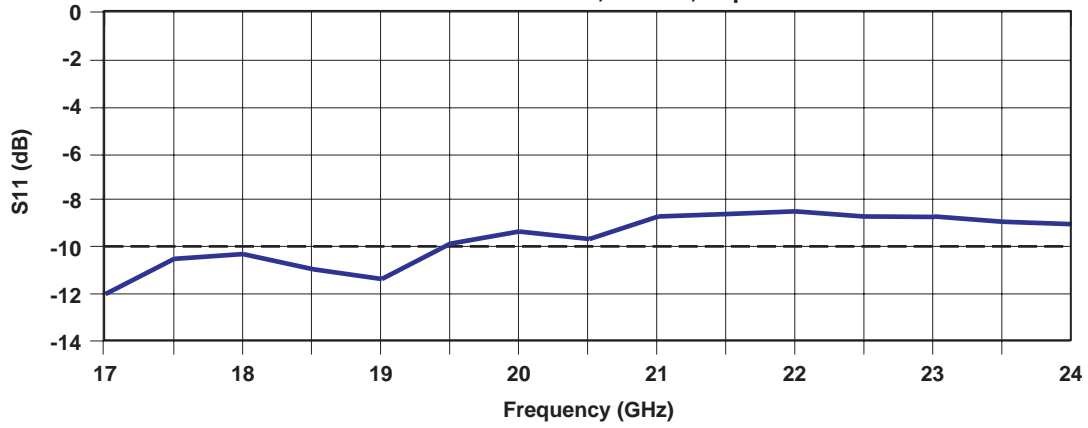
Typical Characteristics

RMWB24001 24 GHz BA, Pout vs Pin Performance
On-Wafer Measurements, $V_d = 4\text{ V}$, $I_{dq} = 70\text{ mA}$

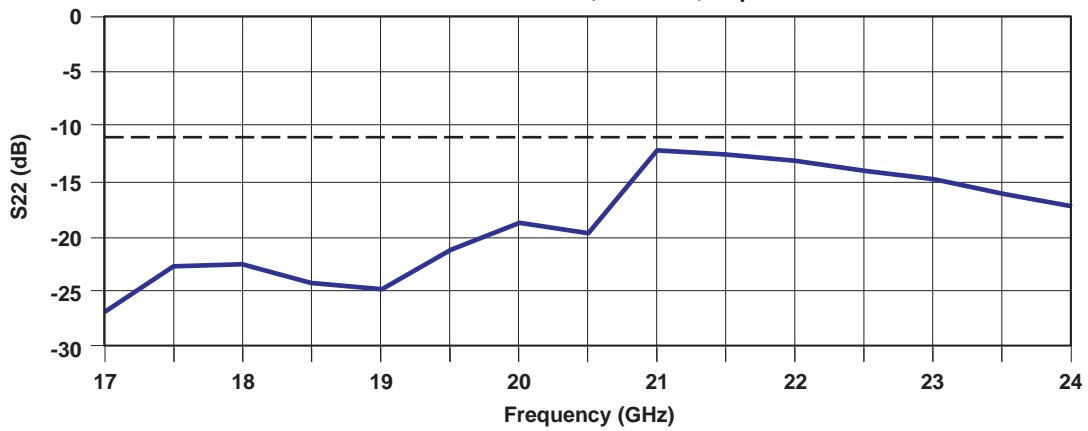


Typical Characteristics (Continued)

RMWB24001 24 GHz BA, Typical Small Signal Performance
On-Wafer Measurements, $V_d = 4\text{ V}$, $I_{dq} = 70\text{ mA}$



RMWB24001 24 GHz BA, Typical Small Signal Performance
On-Wafer Measurements, $V_d = 4\text{ V}$, $I_{dq} = 70\text{ mA}$



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